

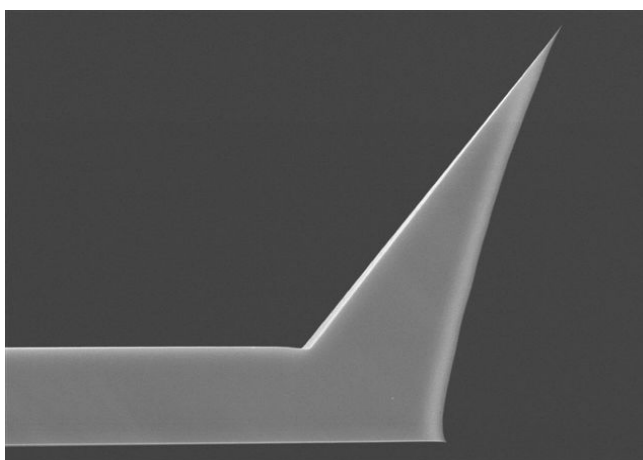
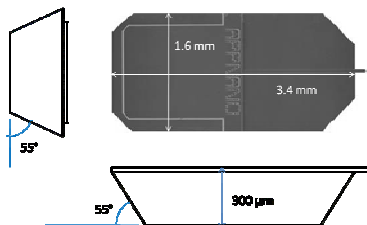
APPNANO probes are compatible with most commercially available SPMs. These probes are nanofabricated using highly doped single crystal silicon with unparalleled reproducibility, robustness and sharpness for consistent high resolution imaging capabilities.

The **ACCESS Probe** is designed for Non-Contact / Tapping Mode / Intermittent Contact / Close Contact applications. Our **ACCESS probes** have a high frequency that allows for faster scanning speeds.

Handle Chip Specifications	
L x W x T	3.4 mm x 1.6 mm x 300 μ m
Alignment Grooves	YES

Tip Specifications	
Shape	Pyramidal
Height (μm)	14 - 16
ROC (nm)	6
Coating	None

Cantilever Specifications	
Material	Si
Shape	Rectangular
Front Coating	None
Reflex Side Coating	None



Parameter	Value		
	Nominal	Minimum	Maximum
Spring Constant (N/m)	50	25	95
Frequency (kHz)	300	200	400
Length (μm)	140	130	150
Width (μm)	50	45	55
Thickness (μm)	5	4.5	5.5